


<b>Search Notes</b>  	<b>Application/Control No.</b>  10679013	<b>Applicant(s)/Patent Under Reexamination</b>  DUPUIS ET AL.
	<b>Examiner</b>  LEILA MALEK	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	377,257,220, and 285	12/18/2008	L.M.
379	90.01,399.01,412	12/18/2008	L.M.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST,IEEE,Consulted M. Ghayour, Inventor Name Search	12/18/2008	L.M.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
375	257,220,285	12/18/2008	L.M.
379	90.01,399.01,412	12/18/2008	L.M.

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